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(71) Applicant (for all designated States except US): **ÉCOLE
POLYTECHNIQUE FÉDÉRALE DE LAUSANNE**
[CH/CH]; CM-Ecublens, CH-1015 Lausanne (CH).

(72) Inventors; and

(75) Inventors/Applicants (for US only): **PLAMANN,
Karsten** [DE/CH]; Institut d'Optique Appliquée, Dé-
partement de Microtechnique, École Polytechnique
Fédérale de Lausanne, CH-1015 Lausanne (CH).
BOURQUIN, Stéphane [CH/CH]; Institut d'Optique
Appliquée, Département de Microtechnique, École Poly-
technique Fédérale de Lausanne, CH-1015 Lausanne
(CH). **DUCROS, Mathieu** [FR/CH]; Institut d'Optique
Appliquée, Département de Microtechnique, École Poly-
technique Fédérale de Lausanne, CH-1015 Lausanne
(CH). **MITIC, Jelena** [YU/CH]; Institut d'Optique
Appliquée, Département de Microtechnique, École Poly-
technique Fédérale de Lausanne, CH-1015 Lausanne
(CH). **VUILLE, François** [CH/CH]; Institut d'Optique
Appliquée, Département de Microtechnique, École Poly-
technique Fédérale de Lausanne, CH-1015 Lausanne (CH).

LASSER, Theo [DE/CH]; Institut d'Optique Appliquée,
Département de Microtechnique, École Polytechnique
Fédérale de Lausanne, CH-1015 Lausanne (CH). **ANHUT,
Tiemo** [DE/CH]; Institut d'Optique Appliqué, Dépt. de
Microtechnique, Ecole Polytechnique Fédérale de Lau-
sanne, CH-1015 Lausanne (CH).

(74) Agents: **SUTCLIFFE, Nicholas, R.** et al.; Mewburn Ellis,
York House 23 Kingsway, London, Greater London WC2B
6HP (GB).

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ning of each regular issue of the PCT Gazette.

(54) Title: MICROSCOPY IMAGING APPARATUS AND MEHOD FOR GENERATING AN IMAGE

(57) Abstract: A method and a microscopy imaging apparatus for generating an optically sectioned image of a specimen are provided. The method comprises the steps of: illuminating the specimen with a modulating, spatially periodic illumination pattern; imaging said specimen on a conjugate image plane; acquiring a plurality of signals at respective positions on said image plane, each signal corresponding to the incident light intensity at that position and having an oscillatory component caused by the modulation of the illumination pattern; and measuring a characteristic of the oscillatory component of each of the signals, whereby the measured characteristics when combined in their relative positions generate an optically sectioned image of the specimen.

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